Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/695,767	WHITTAKER ET AL.	
Examiner	Art Unit	
Patricia T. Nguyen	2817	

	SEAR	CHED	
Class	Subclass	Date	Examiner
330	254	1/31/2005	PN
	285		
	310		
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	INTERFERENCE SEARCHED					
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33	10	254	2/4/2005		PN	
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